

**INFORMATION DISCLOSURE CITATION**  
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ATTY DOCKET NO.

DC4960

SERIAL NO.

09/973,498

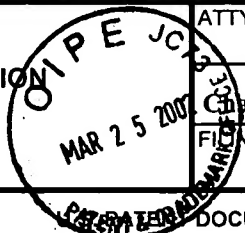
Chaudhury, et. al.

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October 9, 2001

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1713

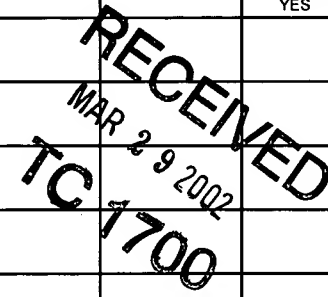


**DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JTK	4,639,285	1/27/87	Suzuki, et. al.	156	272.6	
	4,753,978	6/28/88	Jensen	524	862	
	4,766,176	8/23/88	Lee, et. al.	525	100	
	4,868,096	9/19/89	Nakayama, et. al.	430	329	
	4,897,153	1/30/90	Cole, et. al.	156	643	
	4,933,060	6/12/90	Prohaska, et. al.	204	192.36	
	5,017,654	5/21/91	Togashi, et. al.	525	100	
	5,110,845	5/5/92	Gray, et. al.	523	211	
	5,148,266	9/15/92	Khandros, et. al.	357	80	
	5,344,467	9/6/94	Huang, et. al.	44	358	
JTK	5,346,861	9/13/94	Khandros, et. al.	437	209	

**FOREIGN PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
JTK	JP 06-346034	12/20/94	Japan (abstract only)				
	JP 2000-73029	3/7/00	Japan (abstract only)				
	JP 11-277699	10/12/99	Japan (abstract only)				
	JP 09-214140	8/15/97	Japan (abstract only)				
JTK	JP 08-335608	12/17/96	Japan (abstract only)				



**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

JTK		University of California, Los Angeles, Electronic Materials, Eli Yablonovitch, Vol. 9, pages 219-229.
JTK		Analytical Chemistry, David C. Duffy, et. al., "Rapid Prototyping of Microfluidic Systems in Poly(dimethylsiloxane)" Vol. 70, No. 23, December 1, 1998.

EXAMINER

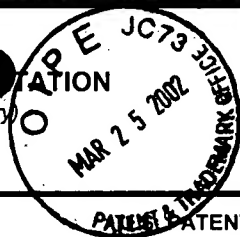
*John T. Haran*

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JTA	5,347,159	9/13/94	Khandros, et. al.	257	692	
	5,357,005	10/18/94	Buchwalter, et. al.	525	436	
	5,477,611	12/26/95	Sweis, et. al.	29	840	
	5,848,467	12/15/98	Khandros, et. al.	29	841	
	5,858,815	1/12/99	Heo, et. al.	438	112	
	5,977,226	11/2/99	Dent, et. al.	524	267	
JTA	6,074,895	6/13/00	Dery, et. al.	438	108	

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
JTA	JP 08-153833	6/11/96	Japan (abstract only)				

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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

JTA	American Chemical Society, "Rate-Dependent Fracture at Adhesive Interface", Manoj K. Chaudhury, May 26, 1999, pages 6562-6566.
JTA	Adhesion '99, Seventh International Conference on Adhesion and Adhesives, Churchill College, Cambridge, UK, September 15 -17, 1999, "Adhesion Measurement of Silicone Thin Films," Bhukan Parbhoo and Manoj K. Chaudhury, pages 350 - 356.

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*[Signature]*

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ATTY DOCKET NO. DC4960	SERIAL NO. 09/973,498
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**U.S. PATENT DOCUMENTS**

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**FOREIGN PATENT DOCUMENTS**

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

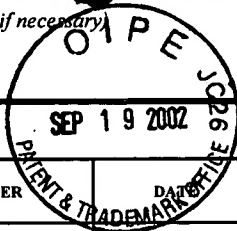
	Langmuir, "Direct Measurement of Interfacial Interactions between Semispherical Lenses and Flat Sheets of Poly(dimethylsiloxane) and Their Chemical Derivatives" Manoj K. Chaudhury and George M. Whitesides, 1991, Vol. 7, pages 1013-1025.

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# INFORMATION DISCLOSURE CITATION

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Docket Number (Optional) <b>DC49</b>	Application Number <b>09/973,498</b>
Applicant(s) <b>Chaudhury, et. al.</b>	
Filing Date <b>October 9, 2001</b>	Group Art Unit <b>1713</b>

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

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## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
<i>JMS</i>		WO 01/61743 A1	8/23/01	Europe			✓	
<i>JMS</i>		WO 02/13247 A1	2/14/02	Europe			✓	
<i>JMS</i>		JP2002-026123A	1/25/02	Japan			✓	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>JMS</i>	2002 Electronic Components and Technology Conference, "Surface Activated Bonding for New Flip Chip and Bumpless Interconnect System", Tadatomo Suga, et. al., Institute for Advanced Micro-system Integration (IMSI), The University of Tokyo, RCAST, Toray Engineering Co. Ltd., 7 pages.

EXAMINER <i>JMS</i>	DATE CONSIDERED <i>9/15/03</i>
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